

SANYO Semiconductors DATA SHEET

P-Channel Silicon MOSFET

EMH2302 — General-Purpose Switching Device **Applications**

Features

- The EMH2302 incorporates a P-channel MOSFET that feature low ON-resistance and ultrahigh-speed switching, thereby enabling high-density mounting.
- 4V drive.

Specifications

Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	P-channel	Unit
Drain-to-Source Voltage	V _{DSS}		-30	V
Gate-to-Source Voltage	VGSS		±20	V
Drain Current (DC)	ID		-2	Α
Drain Current (Pulse)	IDP	PW≤10μs, duty cycle≤1%	-8	Α
Allowable Power Dissipation	PD	Mounted on a ceramic board (900mm ² X0.8mm) 1unit	1.0	W
Total Dissipation	PT	Mounted on a ceramic board (900mm ² X0.8mm)	1.2	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
Drain-to-Source Breakdown Voltage	V(BR)DSS	ID=-1mA, VGS=0V	-30			V
Zero-Gate Voltage Drain Current	IDSS	V _{DS} =-30V, V _{GS} =0V			-1	μΑ
Gate-to-Source Leakage Current	IGSS	V _{GS} =±16V, V _{DS} =0V			±10	μΑ
Cutoff Voltage	VGS(off)	VDS=-10V, ID=-1mA	-1.2		-2.6	V
Forward Transfer Admittance	yfs	V _{DS} =-10V, I _D =-1A	1.3	2.2		S
Static Drain-to-Source On-State Resistance	RDS(on)1	I _D =-1A, V _G S=-10V		115	150	mΩ
	RDS(on)2	ID=-0.5A, VGS=-4V		215	310	mΩ
Input Capacitance	Ciss	V _{DS} =-10V, f=1MHz		285		pF
Output Capacitance	Coss	V _{DS} =-10V, f=1MHz		65		pF
Reverse Transfer Capacitance	Crss	VDS=-10V, f=1MHz		52		pF
Turn-ON Delay Time	t _d (on)	See specified Test Circuit.		8.4		ns
Rise Time	t _r	See specified Test Circuit.		15.5		ns
Turn-OFF Delay Time	t _d (off)	See specified Test Circuit.		29		ns
Fall Time	tf	See specified Test Circuit.		25.5		ns

Marking: MB Continued on next page.

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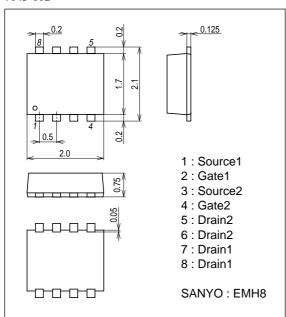
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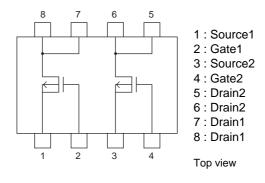
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
Total Gate Charge	Qg	V _{DS} =-10V, V _{GS} =-10V, I _D =-2A		6.7		nC
Gate-to-Source Charge	Qgs	V _{DS} =-10V, V _{GS} =-10V, I _D =-2A		1.1		nC
Gate-to-Drain "Miller" Charge	Qgd	V _{DS} =-10V, V _{GS} =-10V, I _D =-2A		1.05		nC
Diode Forward Voltage	VSD	IS=-2A, VGS=0V		-0.85	-1.2	V

Package Dimensions

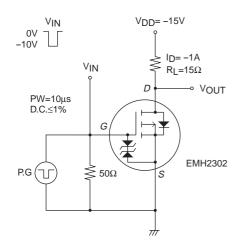
unit : mm (typ) 7045-002

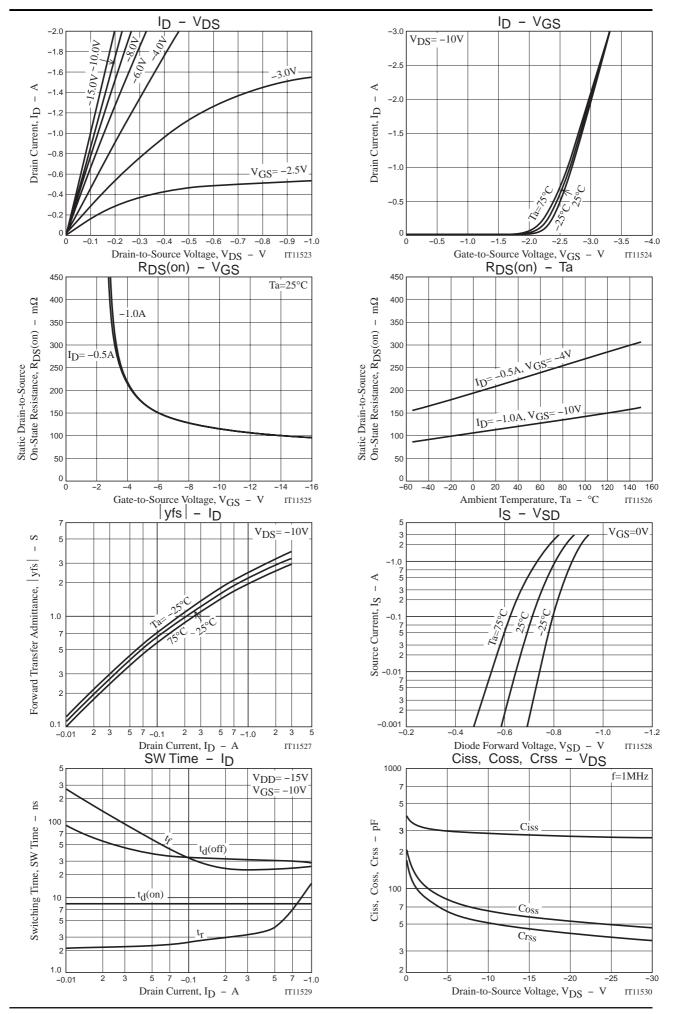


Electrical Connection

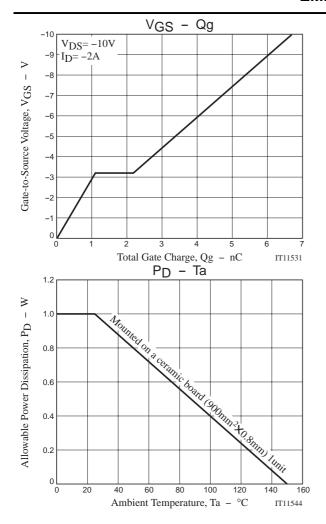


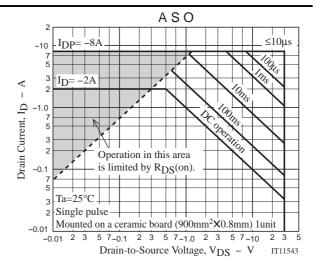
Switching Time Test Circuit





EMH2302





Note on usage: Since the EMH2302 is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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